

The CMS Binary Chip for microstrip tracker readout at the SLHC

OUTLINE



brief review of LHC strip readout architecture CBC design and measured performance first test beam results future directions summary

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CMS LHC tracker



inner & outer barrels, endcaps instrumented by Si microstrips up to \sim 18 cm ($\sim\!25~pF),$ AC coupled

read out by APV25 chips 0.25 μm CMOS power ~ 2.7 mW / channel analogue, unsparsified readout analogue optical link off-detector ~ 200 m² sensor area

- ~ 15,000 detector modules altogether 22 different types
- $\sim 10^7$ strips, $\sim\!75,\!000$ FE chips (APV25)

APV25





SLHC challenges

power consumption

luminosity increases -> higher track density -> higher granularity tracker required => shorter strips and more channels

power delivery

need to bring in power at higher voltages to limit current in cables => serial powering or DC-DC conversion inside tracker

CMS tracker has adopted DC-DC as baseline

triggering

current tracker doesn't contribute to L1 trigger

can't keep SLHC L1 rate at 100 kHz without tracker info => new architectures needed

L=10³⁴ muon trigger rate



CMS Binary Chip (CBC)

what we like about our present system

analog pulse height info (made possible by custom analog link) system simplicity - no on-detector sparsification -> occupancy independent data volume

what must change for SLHC

off-detector links -> high speed digital follows commercial trends

=> large data volumes if keep pulse height info

CBC short strip readout chip prototype for SLHC

binary, unsparsified architecture retains chip and system simplicity but no pulse height

designed for short strips, ~2.5 - 5cm, < ~ 10 pF

full size prototype - 128 channels, 50 µm pitch wire-bond

256 deep pipeline + 32 deep buffer for triggered events

powering test features:

2.5 -> 1.2 DC-DC converter LDO regulator (1.2 -> 1.1) feeds analog FE



2.5 -> 1.25 DC-DC converter

CBC under test

produced in IBM 130 nm CMOS process

2010 CERN MPW run

chips on test bench since Feb. 2011



CBC on test board

basic functionality

communication interfaces

fast: SLVS (Scalable Low Voltage Signalling) - CERN thanks to Sandro Bonacini and Kostas Kloukinas used for 40 MHz clock I/P, L1 trig and data out

slow: I2C - used to programme bias generator operational modes, latency,.. 128 comparator threshold trim values

output data frame

following trigger get 12-bit header

2 start bits, 2 error bits (latency, fifo overflow), 8 bit pipe address followed by 128 channel bits









designed to allow DC coupling

200k resistor feedback absorbs I_{LEAK} noise contribution ~ 200 e 200mV DC shift at O/P for I_{LEAK} =1 μ A

R_f.C_f implements short 20ns diff. time constant => no pile-up issues

works with both sensor polarities

electrons mode (n-in-p)

single 200k resistor, leakage shifts output +ve plenty of headroom

holes mode (p-in-n)

T network (≡ 200k) produces +ve offset leakage shifts output -ve, sufficient headroom for 1 uA

effect of leakage current on preamp O/P waveforms measured on test channel



(note: waveforms include ~ 300 mV offset due to source follower on test channel O/P)

preamp, postamp & comparator



postamp

provides gain and low pass noise filtering overall pulse peaking time 20 nsec gain ~ 50 mV / fC

AC coupling to preamp removes any DC shift from leakage current individually programmable O/P DC level implements channel threshold tuning

comparator

global threshold $V_{\rm CTH}$ programmable hysteresis

S-curves & gain

inject charge and sweep comparator threshold -> s-curve



noise and analogue power

measurement technique

preamp O/P risetime varies with I/P capacitance

risetime $\propto C/g_m \propto C/I_{DS}$ (W.I.)

- => need to vary current in input transistor to keep pulse shape independent of C
- => analogue power consumption will depend on C

noise determined from s-curves

close agreement between measurements (solid symbols) & simulations (open circles)

target spec.: < 1000e for 5 pF sensor measurement: ~ 800e for analog power < 250 μ W/chan

very little difference between electrons and holes modes



comparator - threshold uniformity & tuning

all channels have same global threshold

individual channel tuning achieved by introducing programmable offset at postamp O/P

128 registers, 8-bit precision

before tuning pk-pk threshold spread ~30 mV (~ 0.6 fC)

tuning reduces spread to ~ mV level



128 comparator channels threshold tuning



comparator global threshold [mV]



comparator - timewalk

measure by sweeping time of charge injection always triggering same pipeline location

timewalk spec. < 16 ns between 1.25 and 10 fC signals, with comp. threshold set to 1 fC

measurements just within spec.





powering - LDO



LDO performance



DC measurements

bandgap flat down to 0.9 V

dropout ~ 40 mV for 60 mA load



Power Supply Rejection



AC measurements

need to decouple bandgap output bandgap fed by unregulated LDO input supply => on-chip filter for next iteration

with bandgap decoupled get very good rejection at low frequencies (at limit of measurability)

quite good rejection up to ~ 10 MHz

```
( PSRR = 20log(v<sub>OUT</sub> / v<sub>IN</sub>) )
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converts 2.5V -> ~ 1.2V using 1 MHz clock could be used with 12V -> 2.5V external buck converter (difficult to convert 12 -> 1.2 in 1 step)

could be used to supply VDDD (digital) & analog via LDO

efficiency measured for ~ nominal CBC load $2.52 \text{ V} / 14.2 \text{ mA} \rightarrow 1.2 \text{ V} / 26.4 \text{ mA}$ => ~ 90%

effects on CBC channel noise under study









no measurable dependence on L1 trigger rate (0 – 100 kHz) digital circuitry functions correctly down to $V_{DDD} = 0.9V$

total

180 + (21 x C_{SENSOR}[pF]) μ W / channel

e.g. < 300 uW /channel for 5 pF sensor capacitance

(c.f. APV25 ~2.7 mW / chan. (but long strips))

results with sensor - beta source



count hits in CBC for fixed number of scintillator triggers sweep comparator threshold in 10mV steps -> raw data → fit with curve generated from Landau cross-check signal size with electronic calibration -> most probable signal value ~ 3.5 fC (22,000 e) 840 electrons noise



test beam - first results

CBC + sensor

CBC + sensor operated parasitically in UA9 test

CERN H8 beam line September 2011 beam tracking plane using LHC tracker electronics



future directions

256 channels, bump-bondable

250 μm pitch C4 pads

some issues:

chip and hybrid design has to proceed in parallel - routing capabilities of substrate has impact on pad locations

how to test - prototype and production

plan to submit prototype early 2012



128 channels wirebond: 50 um pitch 7mm x 4mm

> 256 channels bump-bond: 250 um pitch 11.4mm x 4.75mm

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summary

CBC

130 nm CMOS chip for short strips readout at SLHC128 channels of front end amplifier, comparator, pipelineunsparsified binary output data format

measured performance

works for both sensor polarities, can be DC coupled (1 μ A leakage) front end performance close to expectation (noise, gain, ...)

e.g. 800 electrons noise @ < 300 μ W/channel for 5 pF sensor capacitance

lab measurements confirmed in test beam

further testing

more detailed study of powering options temperature effects radiation: ionizing and SEU

next chip iteration

plan to submit 256 channel bump-bondable version, with triggering features, early 2012



extra slides



http://indico.cern.ch/getFile.py/access?contribId=3&sessionId=0&resId=0&materiaIId=0&confId=36580

W.E. / R.H.

CBC modifications for 2-in-1 concept



3 new blocks

cluster width discrimination

wide clusters within a sensor layer not consistent with high PT track - electronically simple correlation

do the stacked tracking operation - electronically relatively simple

trigger data formation and off-chip transmission

options under discussion

either synchronous => limited no. of stubs per BX

or asynchronous => no hard limit, but buffering & timestamping required.

cluster width discrimination



n-1, n, n+1, ... are neighbouring channels on one sensor layer (inner or outer) (but every other channel on chip) could increase to accept wider clusters if necessary

correlation and offset correction

want to correlate cluster in lower layer with cluster occurring within window in upper layer

need programmability of cluster window width width depends on P_T threshold cut (narrower window => higher P_T threshold)

lateral offset of window centre will vary across module





need one of these circuits on every channel programmable register inputs to AND gates to allow for cluster window and offsets between layers

offset varies depending on location across sensor in above example 2 channel offset applied to 3 channel window in outer layer

cluster on channel **n+3** in outer layer correlates with cluster on

channel **n** in inner layer